

Notice of References Cited	Application/Control No. 10/584,733		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner I-CHAN YANG		Art Unit 2178	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,013,424	03-2006	James et al.	715/239
*	B	US-7,305,615	12-2007	Ross, Richard	715/234
*	C	US-6,938,204	08-2005	Hind et al.	715/234
*	D	US-7,080,094	07-2006	Dapp et al.	1/1
*	E	US-2005/0034032	02-2005	Uchida, Masaru	714/048
*	F	US-2004/0083466	04-2004	Dapp et al.	717/143
*	G	US-2004/0088262	05-2004	Boucher et al.	705/065
*	H	US-2004/0221229	11-2004	Perry, Russell	715/514
*	I	US-2005/0138381	06-2005	Stickle et al.	713/176
*	J	US-2006/0106837	05-2006	Choi, Eun-Jeong	707/101
*	K	US-2006/0236224	10-2006	Kuznetsov et al.	715/513
*	L	US-2006/0265689	11-2006	Kuznetsov et al.	717/117
*	M	US-2007/0016554	01-2007	Dapp et al.	707/002

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.